



5/9/2009

RELIABILITY MONITOR REPORT
FOR

MFN 250V Bipolar CMOS DMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX4802CXZ	MAX4802CXZ+	MAX4990ETD+	MAX802CXZ+
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The calculated failure rate for devices using this process is:

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and

Process Information:

Process Description: MFN 250V Bipolar CMOS DMOS

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0834	MAX802CXZ+	150C	1000 HRS	80	0	NEE1HA026Q1
STORAGE LIFE	0834	mAX4802CXZ	150C	1000 HRS	80	0	NEE1HA026Q2
STORAGE LIFE	0834	MAX4802CXZ+	150C	1000 HRS	80	0	NEE1HA026Q3
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0751	MAX4990ETD+	-65C TO 150C	1000 CYS	500	0	NFVZBA008AA
TEMP CYCLE, 5' RAMP, 10' DWELL	0802	MAX4990ETD+	-65C TO 150C	1000 CYS	500	0	NFVZBA004DX
TEMP CYCLE, 5' RAMP, 10' DWELL	0834	MAX4802CXZ	-65C TO 150C	1000 CYS	80	0	NEE1HA026Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	0834	MAX4802CXZ+	-65C TO 150C	1000 CYS	79	0	NEE1HA026Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	0834	MAX4802CXZ	-65C TO 150C	1000 CYS	80	0	NEE1HA026Q3
Total:						0	